18Mb 1x2Lp HSTL High Speed Synchronous SRAMs (512Kb x 36) **Preliminary**

Description

The CXK79M36C162GB is a high speed CMOS synchronous static RAM with common I/O pins. It is manufactured in compliance with the JEDEC-standard 209 pin BGA package pinout defined for SigmaRAM™ devices. It integrates input registers, high speed RAM, output registers, and a two-deep write buffer onto a single monolithic IC. Double Data Rate (DDR) Pipelined (PL) read operations and Late Write (LW) write operations are supported, providing a high-performance user interface. Positive and negative output clocks are provided for applications requiring source-synchronous operation.

All address and control input signals are registered on the rising edge of the CK differential input clock.

During read operations, output data is driven valid twice, from both the rising and falling edges of CK, beginning one full cycle after the address and control signals are registered.

During write operations, input data is registered twice, on both the rising and falling edges of CK, beginning one full cycle after the address and control signals are registered.

Because two pieces of data are always transferred during read and write operations, the least significant address bit of the internal memory array is not available as an external address pin to this device. Consequently, the number of external address pins available to the device is one less than the specified depth of the device (i.e. the 512Kb x 36 device has 18, not 19, external address pins). And, the user cannot choose the order in which the two pieces of data are read. Read data is always provided in the same order in which it is written.

Output drivers are series-terminated, and output impedance is programmable via the ZQ control pin. When an external resistor RQ is connected between ZQ and V_{SS}, the impedance of the SRAM's output drivers is set to ~RQ/5.

300 MHz operation (600 Mbps) is obtained from a single 1.8V power supply. JTAG boundary scan interface is provided using a subset of IEEE standard 1149.1 protocol.

Features

- 3 Speed Bins

	Cycle Time / Data Access Time
-33	3.3ns / 1.8ns
-4	4.0ns / 2.1ns
-5	5.0ns / 2.3ns

- Single 1.8V power supply (V_{DD}): 1.7V (min) to 1.95V (max)
- Dedicated output supply voltage (V_{DDQ}): 1.4V (min) to V_{DD} (max)
- HSTL-compatible I/O interface with dedicated input reference voltage (V_{REF}): $V_{DDQ}/2$ typical
- Common I/O
- Double Data Rate (DDR) data transfers
- Pipelined (PL) read operations
- Late Write (LW) write operations
- Burst capability with internally controlled Linear Burst address sequencing
- Burst length of two or four, with automatic address wrap
- Full read/write data coherency
- Differential input clocks (CK and $\overline{CK}$)
- Data-referenced output clocks (CQ1, $\overline{CQ1}$, CQ2, $\overline{CQ2}$)
- Programmable output driver impedance via dedicated control pin (ZQ)
- Depth expansion capability (2 or 4 banks) via programmable chip enables (E2, E3, EP2, EP3)
- JTAG boundary scan (subset of IEEE standard 1149.1)
- 209 pin (11x19), 1mm pitch, 14mm x 22mm Ball Grid Array (BGA) package

512Kb x 36 Pin Assignment (Top View)

	1	2	3	4	5	6	7	8	9	10	11
A	NC	NC	A	E2	A	ADV	A	E3	A	DQ	DQ
B	NC	NC	MCL (2)	NC	A (x36)	$\overline{W}$	A	MCL (2)	NC	DQ	DQ
C	NC	NC	NC	MCL (2)	NC (144M)	$\overline{E1}$	NC	NC	MCL (2)	DQ	DQ
D	NC	NC	V_{SS}	V_{REF}	NC	MCL	NC	V_{REF}	V_{SS}	DQ	DQ
E	NC	DQ	V_{DDQ}	V_{DDQ}	V_{DD}	V_{DD}	V_{DD}	V_{DDQ}	V_{DDQ}	NC	DQ
F	DQ	DQ	V_{SS}	V_{SS}	V_{SS}	ZQ	V_{SS}	V_{SS}	V_{SS}	NC	NC
G	DQ	DQ	V_{DDQ}	V_{DDQ}	V_{DD}	EP2	V_{DD}	V_{DDQ}	V_{DDQ}	NC	NC
H	DQ	DQ	V_{SS}	V_{SS}	V_{SS}	EP3	V_{SS}	V_{SS}	V_{SS}	NC	NC
J	DQ	DQ	V_{DDQ}	V_{DDQ}	V_{DD}	MCH	V_{DD}	V_{DDQ}	V_{DDQ}	NC	NC
K	CQ2	$\overline{CQ2}$	CK	$\overline{CK}$	V_{SS}	MCL	V_{SS}	NC	NC	$\overline{CQ1}$	CQ1
L	NC	NC	V_{DDQ}	V_{DDQ}	V_{DD}	MCL	V_{DD}	V_{DDQ}	V_{DDQ}	DQ	DQ
M	NC	NC	V_{SS}	V_{SS}	V_{SS}	MCH	V_{SS}	V_{SS}	V_{SS}	DQ	DQ
N	NC	NC	V_{DDQ}	V_{DDQ}	V_{DD}	MCH	V_{DD}	V_{DDQ}	V_{DDQ}	DQ	DQ
P	NC	NC	V_{SS}	V_{SS}	V_{SS}	MCL	V_{SS}	V_{SS}	V_{SS}	DQ	DQ
R	DQ	NC	V_{DDQ}	V_{DDQ}	V_{DD}	V_{DD}	V_{DD}	V_{DDQ}	V_{DDQ}	DQ	NC
T	DQ	DQ	V_{SS}	V_{REF}	NC	MCL	NC	V_{REF}	V_{SS}	NC	NC
U	DQ	DQ	NC	A	NC (72M)	A	NC (36M)	A	NC	NC	NC
V	DQ	DQ	A	A	A	A1	A	A	A	NC	NC
W	DQ	DQ	TMS	TDI	A	MCL (1)	A	TDO	TCK	NC	NC

Notes:

1: Pin 6W is defined as Address Pin A0 in Single Data Rate (SDR) Common I/O SigmaRAMs. However, it must be tied “low” in this device. The least significant address bit of the internal memory array is not available as an externally controlled address pin in Double Data Rate (DDR) Common I/O SigmaRAMs.

2. Pins 3B, 4C, 8B, and 9C are defined as Byte Write Enable Pins $\overline{Bx}$ in x36 Single Data Rate (SDR) Common I/O SigmaRAMs. However, they must be tied “low” in this device. Byte Write functionality is not supported in Double Data Rate (DDR) Common I/O SigmaRAMs.

Pin Description

Symbol	Type	Quantity	Description
A	Input	17	Address Inputs - Registered on the rising edge of CK.
A1	Input	1	Address Input 1 - Registered on the rising edge of CK. Initializes burst counter.
DQ	I/O	36	Data Inputs / Outputs - Registered on the rising and falling edges of CK during write operations. Driven from the rising and falling edges of CK during read operations.
CK, $\overline{CK}$	Input	2	Differential Input Clocks
CQ1, $\overline{CQ1}$ CQ2, $\overline{CQ2}$	Output	4	Output Clocks
$\overline{E1}$	Input	1	Chip Enable Control Input - Registered on the rising edge of CK. $\overline{E1}$ = 0 enables the device to accept read and write commands. $\overline{E1}$ = 1 disables the device. See the Clock Truth Table section for further information.
E2, E3	Input	2	Programmable Chip Enable Control Inputs - Registered on the rising edge of CK. See the Clock Truth Table and Depth Expansion sections for further information.
EP2, EP3	Input	2	Programmable Chip Enable Active-Level Select Inputs - These pins must be tied "high" or "low" at power-up. See the Clock Truth Table and Depth Expansion sections for further information.
ADV	Input	1	Address Advance Control Input - Registered on the rising edge of CK. ADV = 0 loads a new address and begins a new operation when the device is enabled. ADV = 1 increments the address and continues the previous operation when the device is enabled. See the Clock Truth Table section for further information.
$\overline{W}$	Input	1	Write Enable Control Input - Registered on the rising edge of CK. $\overline{W}$ = 0 specifies a write operation when ADV = 0 and the device is enabled. $\overline{W}$ = 1 specifies a read operation when ADV = 0 and the device is enabled. See the Clock Truth Table section for further information.
ZQ	Input	1	Output Impedance Control Resistor Input - This pin must be tied to V_{SS} through an external resistor RQ at power-up. Output driver impedance is set to one-fifth the value of RQ, nominally. See the Output Driver Impedance Control section for further information.
V_{DD}		14	1.8V Core Power Supply - Core supply voltage.
V_{DDQ}		24	Output Power Supply - Output buffer supply voltage.
V_{REF}		4	Input Reference Voltage - Input buffer threshold voltage.
V_{SS}		30	Ground
TCK	Input	1	JTAG Clock
TMS	Input	1	JTAG Mode Select - Weakly pulled "high" internally.
TDI	Input	1	JTAG Data In - Weakly pulled "high" internally.
TDO	Output	1	JTAG Data Out
MCL	*Input*	10	Must Connect "Low" - May not be actual input pins.
MCH	*Input*	3	Must Connect "High" - May not be actual input pins.
NC		52	No Connect - These pins are true no-connects, i.e. there is no internal chip connection to these pins. They can be left unconnected or tied directly to V_{SS}.

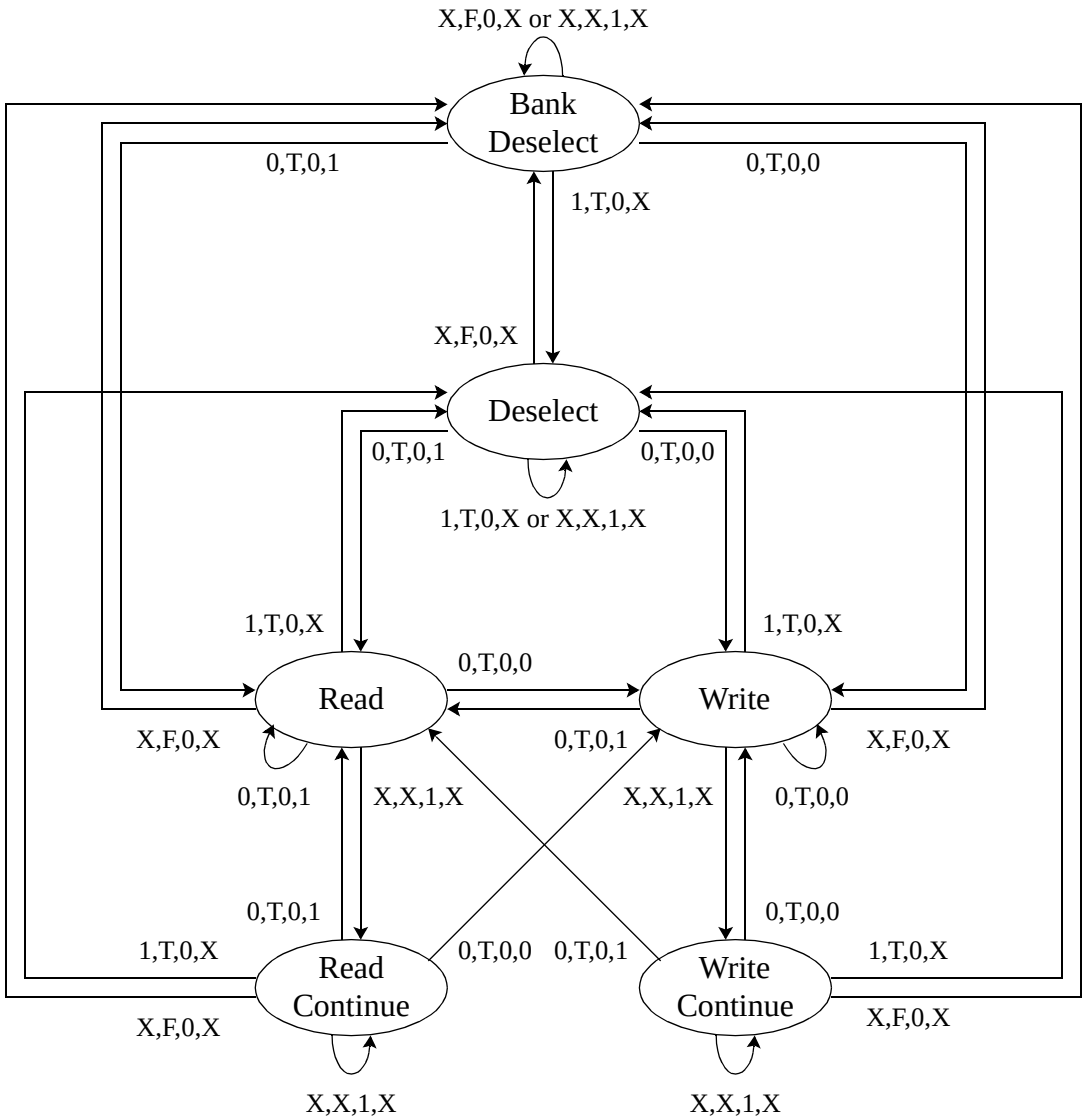
Clock Truth Table

CK	$\overline{E1}$ (t_n)	E (t_n)	ADV (t_n)	$\overline{W}$ (t_n)	Previous Operation	Current Operation	DQ/CQ (t_n)	DQ/CQ ($t_{n+½}$)	DQ/CQ (t_{n+1})	DQ/CQ ($t_{n+1½}$)
↑	X	F	0	X	X	Bank Deselect	***		Hi-Z	
↑	X	X	1	X	Bank Deselect	Bank Deselect (Continue)	Hi-Z		Hi-Z	
↑	1	T	0	X	X	Deselect	***		Hi-Z/CQ	
↑	X	X	1	X	Deselect	Deselect (Continue)	Hi-Z/CQ		Hi-Z/CQ	
↑	0	T	0	0	X	Write Loads new address	***	***	D1/CQ	D2/CQ
↑	X	X	1	X	Write	Write Continue Increments address by 2	D1/CQ	D2/CQ	D3/CQ	D4/CQ
↑	0	T	0	1	X	Read Loads new address	***	***	Q1/CQ	Q2/CQ
↑	X	X	1	X	Read	Read Continue Increments address by 2	Q1/CQ	Q2/CQ	Q3/CQ	Q4/CQ

Notes:

1. "1" = input "high"; "0" = input "low"; "X" = input "don't care"; "T" = input "true"; "F" = input "false".
2. "***" indicates that the DQ input requirement or output state and the CQ output state are determined by the previous operation.
3. If E2 = EP2 and E3 = EP3 then E = "T" else E = "F".
4. DQs are tri-stated in response to Bank Deselect, Deselect, and Write commands, one full cycle after the command is sampled.
5. CQs are tri-stated in response to Bank Deselect commands only, one full cycle after the command is sampled.
6. One (1) Continue operation may be initiated after a Read or Write operation is initiated to burst transfer four (4) distinct pieces of data per single external address input. If a second (2nd) Continue operation is initiated, the internal address wraps back to the initial external (base) address.

State Diagram



Notes:

1. The notation "X,X,X,X" controlling the state transitions above indicate the states of inputs $\overline{E1}$, E, ADV, and $\overline{W}$ respectively.
2. "1" = input "high"; "0" = input "low"; "X" = input "don't care"; "T" = input "true"; "F" = input "false".
3. If E2 = EP2 and E3 = EP3 then E = "T" else E = "F".

•Burst (Continue) Operations

Because two pieces of data are always transferred during read and write operations, the least significant address bit (A0) of the internal memory array is not available as an external address pin to these devices. Rather, the address bit is set to "0" internally prior to the first data transfer and set to "1" internally prior to the second data transfer. Consequently, the two pieces of data transferred during read and write operations are always read in the same address sequence in which they are written.

Burst operations follow the simple address sequence depicted in the table below:

	A1	A1	Sequence Key
1st (Base) Address	0	1	A1
2nd Address	1	0	$\overline{A1}$

One (1) Continue operation may be initiated after a Read or Write operation is initiated to burst transfer four (4) distinct pieces of data per single external address input. If a second (2nd) Continue operation is initiated, the internal address wraps back to the initial external (base) address.

•Depth Expansion

Depth expansion in these devices is supported via programmable chip enables E2 and E3. The active levels of E2 and E3 are programmable through the static inputs EP2 and EP3 respectively. When EP2 is tied "high", E2 functions as an active-high input. When EP2 is tied "low", E2 functions as an active-low input. Similarly, when EP3 is tied "high", E3 functions as an active-high input. And, when EP3 is tied "low", E3 functions as an active-low input.

The programmability of E2 and E3 allows four banks of depth expansion to be accomplished with no additional logic. By programming E2 and E3 of four devices in a binary sequence (00, 01, 10, 11), and by driving E2 and E3 with external address signals, the four devices can be made to look like one larger device.

When these devices are deselected via chip enable $\overline{E1}$, the output clocks continue to toggle. However, when these devices are deselected via programmable chip enables E2 or E3, the output clocks are forced to a Hi-Z state. See the Clock Truth Table for further information.

•Output Driver Impedance Control

The impedance of the data and clock output drivers in these devices can be controlled via the static input ZQ. When an external impedance matching resistor (RQ) is connected between ZQ and V_{SS}, output driver impedance is set to one-fifth the value of the resistor, nominally. See the DC Electrical Characteristics section for further information.

Output driver impedance is updated whenever the data output drivers are in an inactive (High-Z) state. See the Clock Truth Table section for information concerning which commands deactivate the data output drivers.

At power up, 8192 clock cycles followed by any command that deactivates the data output drivers are required to ensure that the output impedance has reached the desired value.

Note: The impedance of the output drivers will drift somewhat due to changes in temperature and voltage. Consequently, during operation, the output drivers should be deactivated periodically in order to update the output impedance and ensure that it remains within specified tolerances.

•Power-Up Sequence

For reliability purposes, Sony recommends that power supplies power up in the following sequence: V_{SS}, V_{DD}, V_{DDQ}, V_{REF}, and Inputs. V_{DDQ} should never exceed V_{DD}. If this power supply sequence cannot be met, a large bypass diode may be required between V_{DD} and V_{DDQ}. Please contact Sony Memory Application Department for further information.

•Absolute Maximum Ratings

Parameter	Symbol	Rating	Units
Supply Voltage	V_{DD}	-0.5 to +2.5	V
Output Supply Voltage	V_{DDQ}	-0.5 to +2.3	V
Input Voltage (Address, Control, Data, Clock) (MCL pins 3B, 8B, 4C, 9C, 6W)	V_{IN}	-0.5 to V_{DDQ}+0.5 (2.3V max)	V
Input Voltage (EP2, EP3) (MCH pins 6J, 6M, 6N) (MCL pins 6D, 6K, 6L, 6P, 6T)	V_{MIN}	-0.5 to V_{DD}+0.5 (2.5V max)	V
Input Voltage (TCK, TMS, TDI)	V_{TIN}	-0.5 to V_{DD}+0.5 (2.5V max)	V
Operating Temperature	T_A	0 to 85	°C
Junction Temperature	T_J	0 to 110	°C
Storage Temperature	T_{STG}	-55 to 150	°C

Note: Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions other than those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

•BGA Package Thermal Characteristics

Parameter	Symbol	Rating	Units
Junction to Case Temperature	Θ_{JC}	3.6	°C/W

•I/O Capacitance

(T_A = 25°C, f = 1 MHz)

Parameter		Symbol	Test conditions	Min	Max	Units
Input Capacitance	Address	C_{IN}	V_{IN} = 0V	---	3.5	pF
	Control	C_{IN}	V_{IN} = 0V	---	3.5	pF
	CK Clock	C_{KIN}	V_{KIN} = 0V	---	4.0	pF
Output Capacitance	Data	C_{OUT}	V_{OUT} = 0V	---	4.5	pF
	CQ Clock	C_{OUT}	V_{OUT} = 0V	---	4.5	pF

Note: These parameters are sampled and are not 100% tested.

•DC Recommended Operating Conditions

(V_{SS} = 0V, T_A = 0 to 85°C)

Parameter	Symbol	Min	Typ	Max	Units	Notes
Supply Voltage	V_{DD}	1.7	1.8	1.95	V	
Output Supply Voltage	V_{DDQ}	1.4	---	V_{DD}	V	
Input Reference Voltage	V_{REF}	$V_{DDQ}/2$ - 0.1	$V_{DDQ}/2$	$V_{DDQ}/2$ + 0.1	V	1
Input High Voltage (Address, Control, Data)	V_{IH}	V_{REF} + 0.2	---	V_{DDQ} + 0.3	V	2
Input Low Voltage (Address, Control, Data)	V_{IL}	-0.3	---	V_{REF} - 0.2	V	3
Input High Voltage (EP2, EP3, MCH)	V_{MIH}	V_{REF} + 0.3	---	V_{DD} + 0.3	V	
Input Low Voltage (EP2, EP3, MCL)	V_{MIL}	-0.3	---	V_{REF} - 0.3	V	
Clock Input Signal Voltage	V_{KIN}	-0.3	---	V_{DDQ} + 0.3	V	2,3
Clock Input Differential Voltage	V_{DIF}	0.4	---	V_{DDQ} + 0.6	V	
Clock Input Common Mode Voltage	V_{CM}	$V_{DDQ}/2$ - 0.1	$V_{DDQ}/2$	$V_{DDQ}/2$ + 0.1	V	

1. The peak-to-peak AC component superimposed on V_{REF} may not exceed 5% of the DC component.
2. V_{IH} (max) AC = V_{DDQ} + 0.9V for pulse widths less than one-quarter of the cycle time ($t_{CYC}/4$).
3. V_{IL} (min) AC = -0.9V for pulse widths less than one-quarter of the cycle time ($t_{CYC}/4$).

•DC Electrical Characteristics

(V_{DD} = 1.8V ± 0.1V, V_{SS} = 0V, T_A = 0 to 85°C)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units	Notes
Input Leakage Current (Address, Control, Clock)	I_{LI}	V_{IN} = V_{SS} to V_{DDQ}	-5	---	5	uA	
Input Leakage Current (EP2, EP3)	I_{MLI1}	V_{MIN} = V_{SS} to V_{DD}	-10	---	10	uA	
Input Leakage Current (MCH)	I_{MLI2}	V_{MIN} = V_{MIH} (min) to V_{DD}	-10	---	10	uA	
Input Leakage Current (MCL)	I_{MLI3}	V_{MIN} = V_{SS} to V_{MIL} (max)	-10	---	10	uA	
Output Leakage Current	I_{LO}	V_{OUT} = V_{SS} to V_{DDQ}	-10	---	10	uA	
Average Power Supply Operating Current	I_{DD-33} I_{DD-4} I_{DD-5}	I_{OUT} = 0 mA V_{IN} = V_{IH} or V_{IL}	--- --- ---	--- --- ---	750 650 550	mA	
Power Supply Deselect Operating Current	I_{DD2}	I_{OUT} = 0 mA V_{IN} = V_{IH} or V_{IL}	---	---	250	mA	
Output High Voltage	V_{OH}	I_{OH} = -7.0 mA RQ = 250Ω	V_{DDQ} - 0.4	---	---	V	
Output Low Voltage	V_{OL}	I_{OL} = 7.0 mA RQ = 250Ω	---	---	0.4	V	
Output Driver Impedance	R_{OUT}	V_{OH}, V_{OL} = V_{DDQ}/2 RQ < 150Ω	---	---	35 (30*1.15)	Ω	1
		V_{OH}, V_{OL} = V_{DDQ}/2 150Ω ≤ RQ ≤ 300Ω	(RQ/5)* 0.85	RQ/5	(RQ/5)* 1.15	Ω	
		V_{OH}, V_{OL} = V_{DDQ}/2 RQ > 300Ω	51 (60*0.85)	---	---	Ω	2

1. For maximum output drive (i.e. minimum impedance), the ZQ pin can be tied directly to V_{SS}.
2. For minimum output drive (i.e. maximum impedance), the ZQ pin can be left unconnected or tied directly to V_{DDQ}.

•AC Electrical Characteristics

(V_{DD} = 1.8V ± 0.1V, V_{SS} = 0V, T_A = 0 to 85°C)

Parameter	Symbol	-33		-4		-5		Units	Notes
		Min	Max	Min	Max	Min	Max		
Input Clock Cycle Time	t_{KHKH}	3.3	---	4.0	---	5.0	---	ns	
Input Clock High Pulse Width	t_{KHKL}	1.3	---	1.5	---	2.0	---	ns	
Input Clock Low Pulse Width	t_{KLKH}	1.3	---	1.5	---	2.0	---	ns	
Address Input Setup Time	t_{AVKH}	0.7	---	0.8	---	1.0	---	ns	
Address Input Hold Time	t_{KHAX}	0.4	---	0.5	---	0.5	---	ns	
Control Input Setup Time	t_{BVKH}	0.7	---	0.8	---	1.0	---	ns	1
Control Input Hold Time	t_{KHBX}	0.4	---	0.5	---	0.5	---	ns	1
Data Input Setup Time	t_{DVKH} t_{DVKL}	0.35	---	0.4	---	0.45	---	ns	
Data Input Hold Time	t_{KHDX} t_{KLDX}	0.3	---	0.35	---	0.4	---	ns	
Input Clock High to Output Data Valid Input Clock Low to Output Data Valid	t_{KHQV} t_{KLQV}	---	1.8	---	2.1	---	2.3	ns	
Input Clock High to Output Data Hold Input Clock Low to Output Data Hold	t_{KHQX} t_{KLQX}	0.5	---	0.5	---	0.5	---	ns	2
Input Clock High to Output Data Low-Z	t_{KHQX1}	0.5	---	0.5	---	0.5	---	ns	2,3
Input Clock High to Output Data High-Z	t_{KHQZ}	---	1.8	---	2.1	---	2.3	ns	2,3
Input Clock High to Output Clock High Input Clock Low to Output Clock Low	t_{KHCH} t_{KLCL}	0.5	1.8	0.5	2.1	0.5	2.3	ns	
Input Clock High to Output Clock Low-Z	t_{KHCX1}	0.5	---	0.5	---	0.5	---	ns	2,3
Input Clock High to Output Clock High-Z	t_{KHCZ}	---	1.8	---	2.1	---	2.3	ns	2,3
Output Clock High to Output Data Valid Output Clock Low to Output Data Valid	t_{CHQV} t_{CLQV}	---	0.25	---	0.25	---	0.3	ns	2
Output Clock High to Output Data Hold Output Clock Low to Output Data Hold	t_{CHQX} t_{CLQX}	-0.25	---	-0.25	---	-0.3	---	ns	2

All parameters are measured from the mid-point of the object signal to the mid-point of the reference signal, unless otherwise noted.

1. These parameters apply to control inputs $\overline{E1}$, E2, E3, ADV, and $\overline{W}$.

2. These parameters are guaranteed by design through extensive corner lot characterization.

3. These parameters are measured at ± 50mV from steady state voltage.

•AC Electrical Characteristics (Note)

The four AC timing parameters listed below are tested according to specific combinations of Output Clocks (CQs) and Output Data (DQs):

1. t_{CHQV} - Output Clock High to Output Data Valid (max)
2. t_{CLQV} - Output Clock Low to Output Data Valid (max)
3. t_{CHQX} - Output Clock High to Output Data Hold (min)
4. t_{CLQX} - Output Clock Low to Output Data Hold (min)

The specific CQ / DQ combinations are defined as follows:

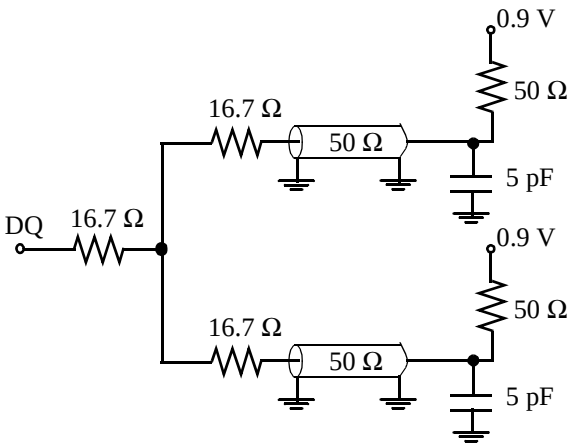
512Kb x 36	
CQs	DQs
1K, 2K	2E, 1F, 2F, 1G, 2G, 1H, 2H, 1J, 2J, 1R, 1T, 2T, 1U, 2U, 1V, 2V, 1W, 2W
10K, 11K	10A, 11A, 10B, 11B, 10C, 11C, 10D, 11D, 11E, 10L, 11L, 10M, 11M, 10N, 11N, 10P, 11P, 10R

•AC Test Conditions (V_{DDQ} = 1.8V)

(V_{DD} = 1.8V ± 0.1V, V_{DDQ} = 1.8V ± 0.1V, T_A = 0 to 85°C)

Parameter	Symbol	Conditions	Units	Notes
Input Reference Voltage	V_{REF}	0.9	V	
Input High Level	V_{IH}	1.4	V	
Input Low Level	V_{IL}	0.4	V	
Input Rise & Fall Time		2.0	V/ns	
Input Reference Level		0.9	V	
Clock Input High Voltage	V_{KIH}	1.4	V	V_{DIF} = 1.0V
Clock Input Low Voltage	V_{KIL}	0.4	V	V_{DIF} = 1.0V
Clock Input Common Mode Voltage	V_{CM}	0.9	V	
Clock Input Rise & Fall Time		2.0	V/ns	
Clock Input Reference Level		CK/$\overline{CK}$ cross	V	
Output Reference Level		0.9	V	
Output Load Conditions		RQ = 250Ω		See Figure 1 below

Figure 1: AC Test Output Load (V_{DDQ} = 1.8V)

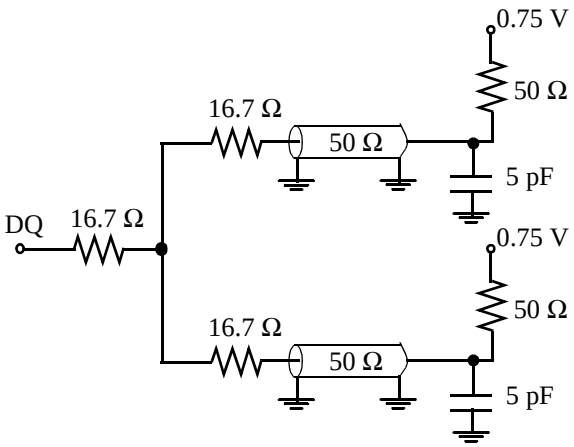


•AC Test Conditions (V_{DDQ} = 1.5V)

(V_{DD} = 1.8V ± 0.1V, V_{DDQ} = 1.5V ± 0.1V, T_A = 0 to 85°C)

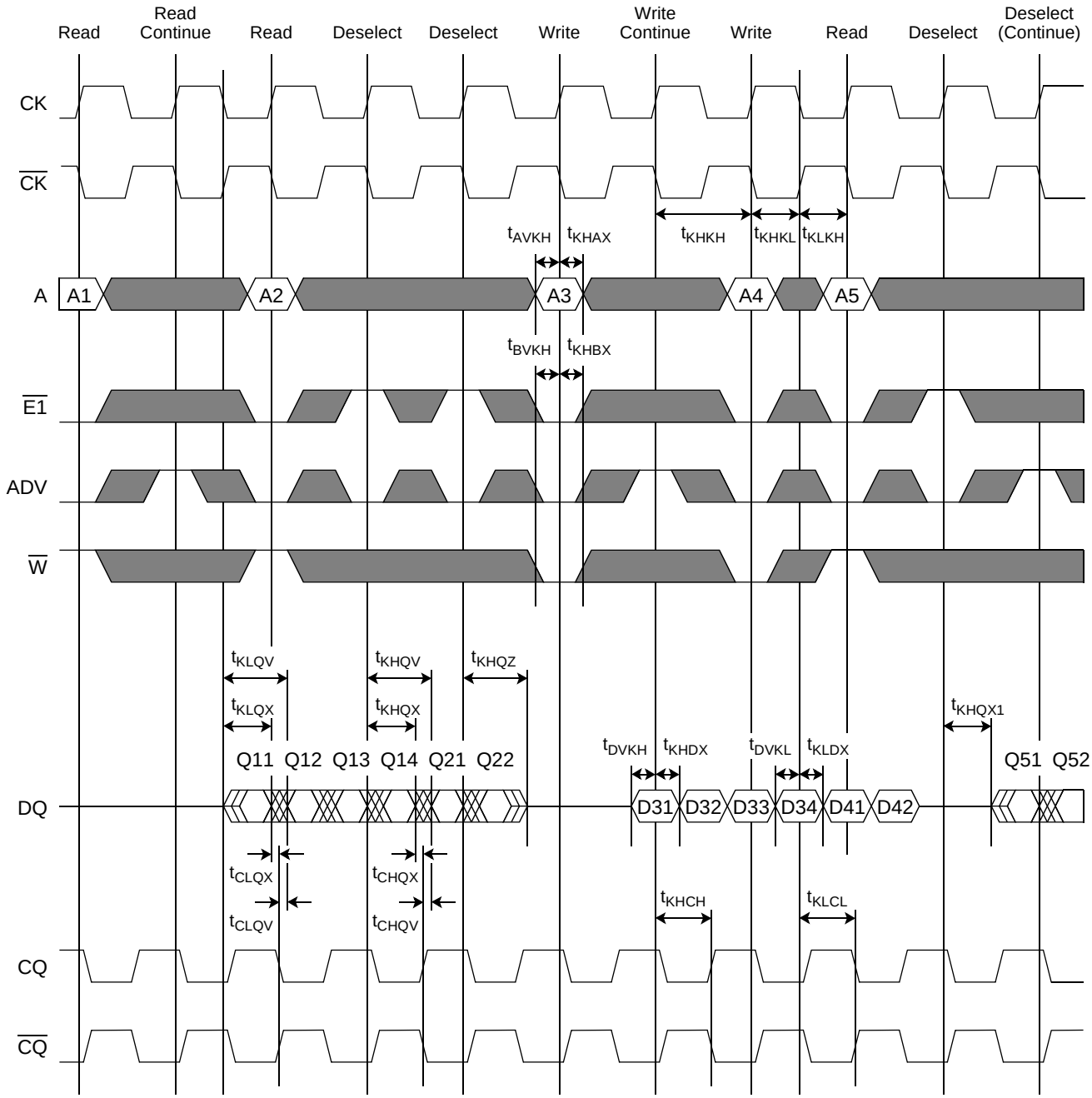
Parameter	Symbol	Conditions	Units	Notes
Input Reference Voltage	V_{REF}	0.75	V	
Input High Level	V_{IH}	1.25	V	
Input Low Level	V_{IL}	0.25	V	
Input Rise & Fall Time		2.0	V/ns	
Input Reference Level		0.75	V	
Clock Input High Voltage	V_{KIH}	1.25	V	V_{DIF} = 1.0V
Clock Input Low Voltage	V_{KIL}	0.25	V	V_{DIF} = 1.0V
Clock Input Common Mode Voltage	V_{CM}	0.75	V	
Clock Input Rise & Fall Time		2.0	V/ns	
Clock Input Reference Level		CK/$\overline{CK}$ cross	V	
Output Reference Level		0.75	V	
Output Load Conditions		RQ = 250Ω		See Figure 2 below

Figure 2: AC Test Output Load (V_{DDQ} = 1.5V)



One Bank Read-Write-Read Timing Diagram

Figure 3

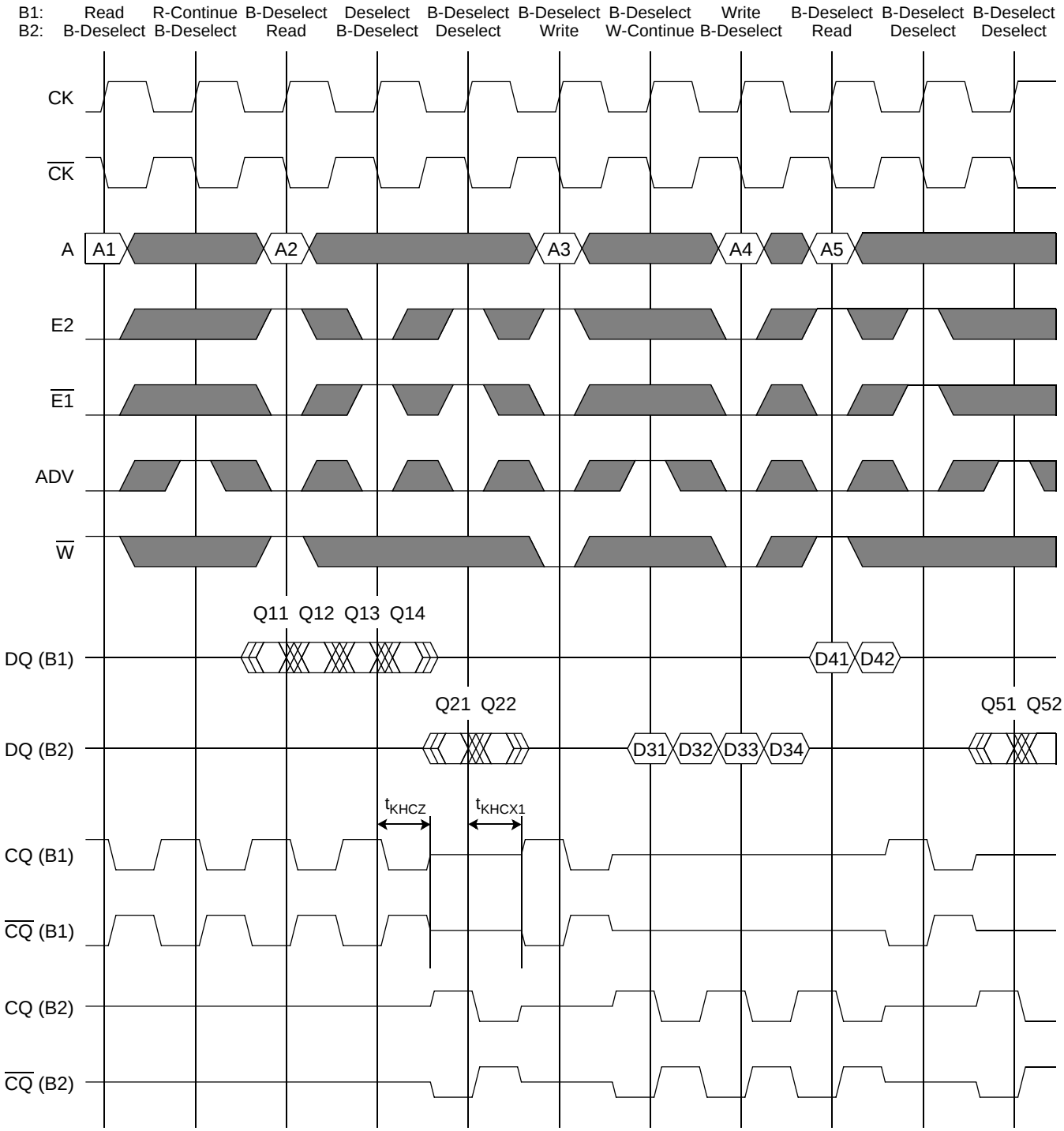


Note: In the diagram above, two Deselect operations are inserted between Read and Write operations to control the data bus transition from output to input. This depiction is for clarity purposes only. It is NOT a requirement. Depending on the application, one Deselect operation may be sufficient.

Note: E1 = EP1 and E2 = EP2 in this example (not shown).

Two Bank Read-Write-Read Timing Diagram

Figure 4



Note: In the diagram above, two Deselect operations are inserted between Read and Write operations to control the data bus transition from output to input. This depiction is for clarity purposes only. It is NOT a requirement. Depending on the application, one Deselect operation may be sufficient.

Note: Bank 1 EP1 = "low", Bank 2 EP1 "high", and Bank 1 and Bank 2 E2 = EP2 in this example (not shown).

•Test Mode Description

These devices provide a JTAG Test Access Port (TAP) and Boundary Scan interface using a limited set of IEEE std. 1149.1 functions. This test mode is intended to provide a mechanism for testing the interconnect between master (processor, controller, etc.), SRAMs, other components, and the printed circuit board.

In conformance with a subset of IEEE std. 1149.1, these devices contain a TAP Controller and four TAP Registers. The TAP Registers consist of one Instruction Register and three Data Registers (ID, Bypass, and Boundary Scan Registers).

The TAP consists of the following four signals:

TCK:	Test Clock	Induces (clocks) TAP Controller state transitions.
TMS:	Test Mode Select	Inputs commands to the TAP Controller. Sampled on the rising edge of TCK.
TDI:	Test Data In	Inputs data serially to the TAP Registers. Sampled on the rising edge of TCK.
TDO:	Test Data Out	Outputs data serially from the TAP Registers. Driven from the falling edge of TCK.

Disabling the TAP

When JTAG is not used, TCK should be tied "low" to prevent clocking the SRAM. TMS and TDI should either be tied "high" through a pull-up resistor or left unconnected. TDO should be left unconnected.

Note: Operation of the TAP does not disrupt normal SRAM operation except when the EXTEST-A or SAMPLE-Z instruction is selected. Consequently, TCK, TMS, and TDI can be controlled any number of ways without adversely affecting the functionality of the device.

JTAG DC Recommended Operating Conditions

(V_{DD} = 1.8V ± 0.1V, T_A = 0 to 85°C)

Parameter	Symbol	Test Conditions	Min	Max	Units
JTAG Input High Voltage (TCK, TMS, TDI)	V_{TIH}	---	$V_{DD}/2 + 0.3$	$V_{DD} + 0.3$	V
JTAG Input Low Voltage (TCK, TMS, TDI)	V_{TIL}	---	-0.3	$V_{DD}/2 - 0.3$	V
JTAG Output High Voltage (TDO)	V_{TOH}	I_{TOH} = -100uA	$V_{DD} - 0.1$	---	V
JTAG Output Low Voltage (TDO)	V_{TOL}	I_{TOL} = 100uA	---	0.1	V
JTAG Output High Voltage (TDO)	V_{TOH}	I_{TOH} = -8mA	$V_{DD} - 0.4$	---	V
JTAG Output Low Voltage (TDO)	V_{TOL}	I_{TOL} = 8mA	---	0.4	V
JTAG Input Leakage Current	I_{TLI}	$V_{TIN} = V_{SS}$ to V_{DD}	-20	10	uA
JTAG Output Leakage Current	I_{TLO}	$V_{TOUT} = V_{SS}$ to V_{DD}	-10	10	uA

JTAG AC Test Conditions

(V_{DD} = 1.8V ± 0.1V, T_A = 0 to 85°C)

Parameter	Symbol	Conditions	Units	Notes
JTAG Input High Level	V_{TIH}	1.8	V	
JTAG Input Low Level	V_{TIL}	0.0	V	
JTAG Input Rise & Fall Time		1.0	V/ns	
JTAG Input Reference Level		0.9	V	
JTAG Output Reference Level		0.9	V	
JTAG Output Load Condition				See Fig. 1 (page 12)

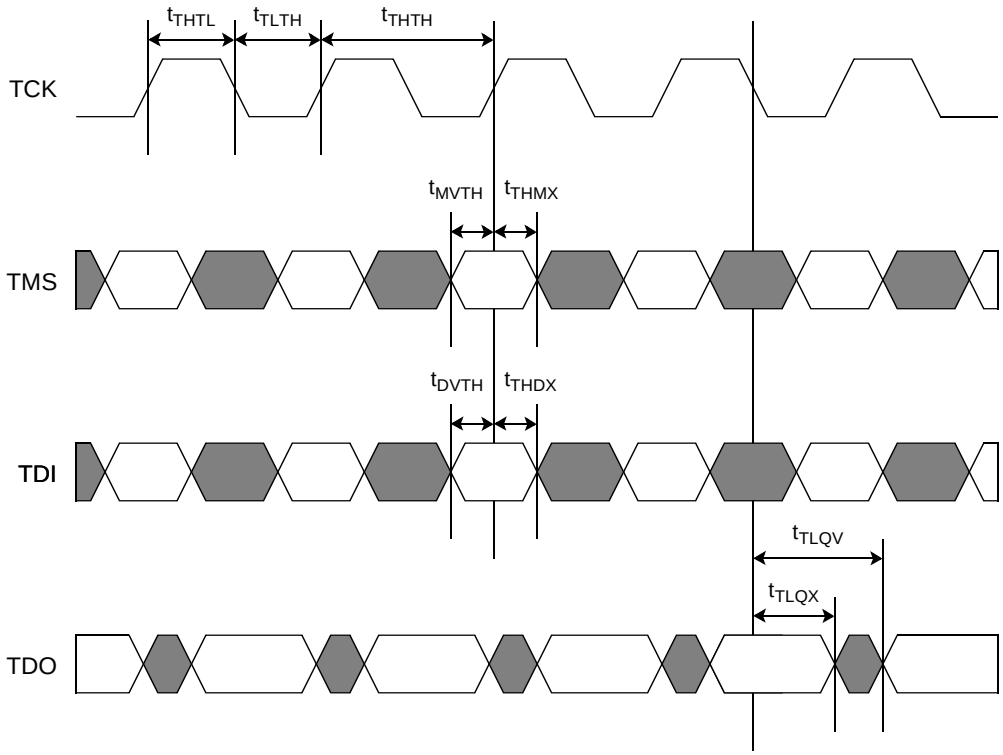
JTAG AC Electrical Characteristics

Parameter	Symbol	Min	Max	Units	Notes
TCK Cycle Time	t_{THTH}	50		ns	
TCK High Pulse Width	t_{THTL}	20		ns	
TCK Low Pulse Width	t_{TLTH}	20		ns	
TMS Setup Time	t_{MVTH}	5		ns	
TMS Hold Time	t_{THMX}	5		ns	
TDI Setup Time	t_{DVTH}	5		ns	
TDI Hold Time	t_{THDX}	5		ns	
Capture Setup Time (Address, Control, Data, Clock)	t_{CS}	5		ns	1
Capture Hold Time (Address, Control, Data, Clock)	t_{CH}	8		ns	1
TCK Low to TDO Valid	t_{TLQV}		10	ns	
TCK Low to TDO Hold	t_{TLQX}	0		ns	

1. These parameters are guaranteed by design through extensive corner lot characterization.

JTAG Timing Diagram

Figure 5



TAP Controller

The TAP Controller is a 16-state state machine that controls access to the various TAP Registers and executes the operations associated with each TAP Instruction. State transitions are controlled by TMS and occur on the rising edge of TCK.

The TAP Controller enters the “Test-Logic Reset” state in one of two ways:

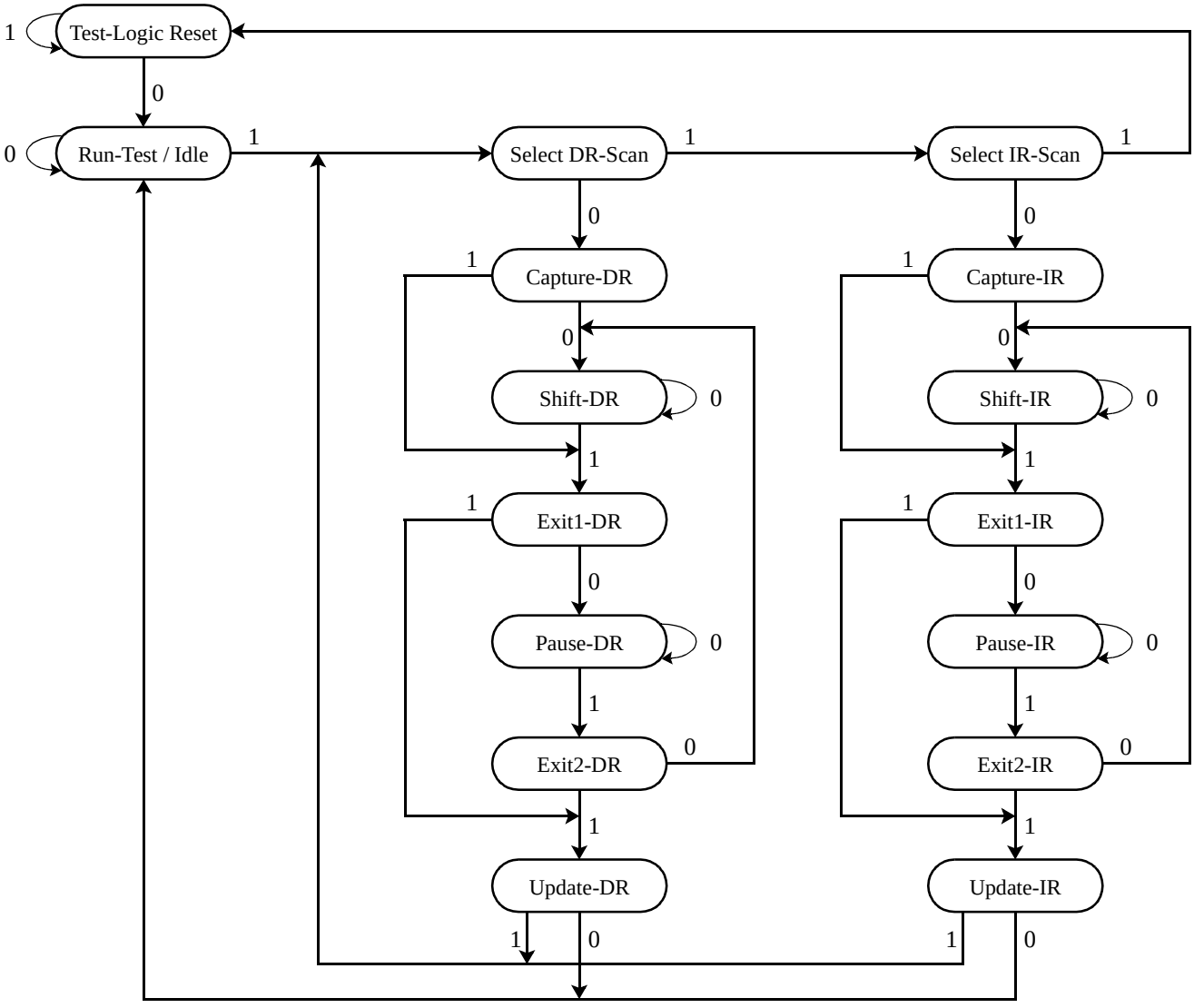
1. At power up.
2. When a logic “1” is applied to TMS for at least 5 consecutive rising edges of TCK.

The TDI input receiver is sampled only when the TAP Controller is in either the “Shift-IR” state or the “Shift-DR” state.

The TDO output driver is active only when the TAP Controller is in either the “Shift-IR” state or the “Shift-DR” state.

TAP Controller State Diagram

Figure 6



TAP Registers

TAP Registers are serial shift registers that capture serial input data (from TDI) on the rising edge of TCK, and drive serial output data (to TDO) on the subsequent falling edge of TCK. They are divided into two groups: "Instruction Registers" (IR), which are manipulated via the "IR" states in the TAP Controller, and "Data Registers" (DR), which are manipulated via the "DR" states in the TAP Controller.

Instruction Register (IR - 3 bits)

The Instruction Register stores the various TAP Instructions supported by these devices. It is loaded with the IDCODE instruction at power-up, and when the TAP Controller is in the "Test-Logic Reset" and "Capture-IR" states. It is inserted between TDI and TDO when the TAP Controller is in the "Shift-IR" state, at which time it can be loaded with a new instruction. However, newly loaded instructions are not executed until the TAP Controller has reached the "Update-IR" state.

The Instruction Register is 3 bits wide, and is encoded as follows:

Code (2:0)	Instruction	Description
000	EXTEST-A	Loads the individual logic states of all signals composing the SRAM's I/O ring into the Boundary Scan Register when the TAP Controller is in the "Capture-DR" state, and inserts the B-Scan Register between TDI and TDO when the TAP Controller is in the "Shift-DR" state. Also enables the SRAM's data and clock output drivers, and moves the contents of the B-Scan Register associated with the data and clock output signals to the input side of the SRAM's output register. The SRAM's input clock can then be used to transfer the B-Scan Register contents directly to the data and clock output pins (the input clock controls the SRAM's output register). Note that newly captured and/or shifted B-Scan Register contents do not appear at the input side of the SRAM's output register until the TAP Controller has reached the "Update-DR" state. See the Boundary Scan Register description for more information.
001	IDCODE	Loads a predefined device- and manufacturer-specific identification code into the ID Register when the TAP Controller is in the "Capture-DR" state, and inserts the ID Register between TDI and TDO when the TAP Controller is in the "Shift-DR" state. See the ID Register description for more information.
010	SAMPLE-Z	Loads the individual logic states of all signals composing the SRAM's I/O ring into the Boundary Scan Register when the TAP Controller is in the "Capture-DR" state, and inserts the B-Scan Register between TDI and TDO when the TAP Controller is in the "Shift-DR" state. Also disables the SRAM's data and clock output drivers. See the Boundary Scan Register description for more information.
011	PRIVATE	Do not use. Reserved for manufacturer use only.
100	SAMPLE	Loads the individual logic states of all signals composing the SRAM's I/O ring into the Boundary Scan Register when the TAP Controller is in the "Capture-DR" state, and inserts the B-Scan Register between TDI and TDO when the TAP Controller is in the "Shift-DR" state. See the Boundary Scan Register description for more information.
101	PRIVATE	Do not use. Reserved for manufacturer use only.
110	PRIVATE	Do not use. Reserved for manufacturer use only.
111	BYPASS	Loads a logic "0" into the Bypass Register when the TAP Controller is in the "Capture-DR" state, and inserts the Bypass Register between TDI and TDO when the TAP Controller is in the "Shift-DR" state. See the Bypass Register description for more information.

Bit 0 is the LSB of the Instruction Register, and Bit 2 is the MSB. When the Instruction Register is selected, TDI serially shifts data into the MSB, and the LSB serially shifts data out through TDO.

Bypass Register (DR - 1 bit)

The Bypass Register is one bit wide, and provides the minimum length serial path between TDI and TDO. It is loaded with a logic "0" when the BYPASS instruction has been loaded in the Instruction Register and the TAP Controller is in the "Capture-DR" state. It is inserted between TDI and TDO when the BYPASS instruction has been loaded into the Instruction Register and the TAP Controller is in the "Shift-DR" state.

ID Register (DR - 32 bits)

The ID Register is loaded with a predetermined device- and manufacturer-specific identification code when the IDCODE instruction has been loaded into the Instruction Register and the TAP Controller is in the "Capture-DR" state. It is inserted between TDI and TDO when the IDCODE instruction has been loaded into the Instruction Register and the TAP Controller is in the "Shift-DR" state.

The ID Register is 32 bits wide, and is encoded as follows:

Device	Revision Number (31:28)	Part Number (27:12)	Sony ID (11:1)	Start Bit (0)
512Kb x 36	xxxx	0000 0000 0101 1011	0000 1110 001	1

Bit 0 is the LSB of the ID Register, and Bit 31 is the MSB. When the ID Register is selected, TDI serially shifts data into the MSB, and the LSB serially shifts data out through TDO.

Boundary Scan Register (DR - 84 bits)

The Boundary Scan Register is equal in length to the number of active signal connections to the SRAM (excluding the TAP pins) plus a number of place holder locations reserved for functional and/or density upgrades. It is loaded with the individual logic states of all signals composing the SRAM's I/O ring when the EXTEST-A, SAMPLE, or SAMPLE-Z instruction has been loaded into the Instruction Register and the TAP Controller is in the "Capture-DR" state. It is inserted between TDI and TDO when the EXTEST-A, SAMPLE, or SAMPLE-Z instruction has been loaded into the Instruction Register and the TAP Controller is in the "Shift-DR" state.

The Boundary Scan Register contains the following bits:

512Kb x 36	
DQx	36
A, A1	18
CK, $\overline{CK}$	2
CQ1, CQ2, $\overline{CQ1}$, $\overline{CQ2}$	4
$\overline{E1}$, ADV, $\overline{W}$	3
E2, E3, EP2, EP3	4
ZQ	1
Place Holder	16

Note: CK and $\overline{CK}$ are connected to a differential input receiver that generates a single-ended input clock to these devices. Therefore, in order to capture deterministic values for these signals in the Boundary Scan Register, they must be at opposite logic levels when sampled.

Note: When an external resistor RQ is connected between the ZQ pin and V_{SS}, the value of the ZQ signal captured in the Boundary Scan Register is non-deterministic.

Boundary Scan Register Bit Order Assignments

The tables below depict the order in which the bits are arranged in the Boundary Scan Register. Bit 1 is the LSB and bit 84 is the MSB. When the Boundary Scan Register is selected, TDI serially shifts data into the MSB, and the LSB serially shifts data out through TDO.

512Kb x 36								
Bit	Signal	Pad	Bit	Signal	Pad	Bit	Signal	Pad
1	NC (1)	5C	36	E3	8A	71	MCH	6J
2	NC (1)	5U	37	A	7B	72	A	3V
3	NC (1)	7U	38	A	7A	73	A	4V
4	MCL (1)	6D	39	$\overline{W}$	6B	74	A	4U
5	MCL (1)	6K	40	ADV	6A	75	A	5V
6	MCL (1)	6P	41	$\overline{E1}$	6C	76	A	6U
7	MCL (1)	6T	42	A	5A	77	A	5W
8	MCH (2)	6N	43	A	5B	78	MCL	6W
9	MCH	6M	44	E2	4A	79	A1	6V
10	MCL	6L	45	A	3A	80	A	7V
11	DQ	10R	46	ZQ	6F	81	A	8V
12	DQ	11P	47	MCL	4C	82	A	7W
13	DQ	10P	48	MCL	3B	83	A	8U
14	DQ	11N	49	DQ	2E	84	A	9V
15	DQ	10N	50	DQ	1F			
16	DQ	11M	51	DQ	2F			
17	DQ	10M	52	DQ	1G			
18	DQ	11L	53	DQ	2G			
19	DQ	10L	54	DQ	1H			
20	CQ1	11K	55	DQ	2H			
21	$\overline{CQ1}$	10K	56	DQ	1J			
22	DQ	11E	57	DQ	2J			
22	DQ	10D	58	CQ2	1K			
24	DQ	11D	59	CK	3K			
25	DQ	10C	60	$\overline{CK}$	4K			
26	DQ	11C	61	$\overline{CQ2}$	2K			
27	DQ	10B	62	DQ	1R			
28	DQ	11B	63	DQ	2T			
29	DQ	11A	64	DQ	1T			
30	DQ	10A	65	DQ	2U			
31	MCL	9C	66	DQ	1U			
32	MCL	8B	67	DQ	2V			
33	EP3	6H	68	DQ	1V			
34	EP2	6G	69	DQ	1W			
35	A	9A	70	DQ	2W			

Note 1: These NC and MCL pins are connected to V_{SS} internally, regardless of pin connection externally.

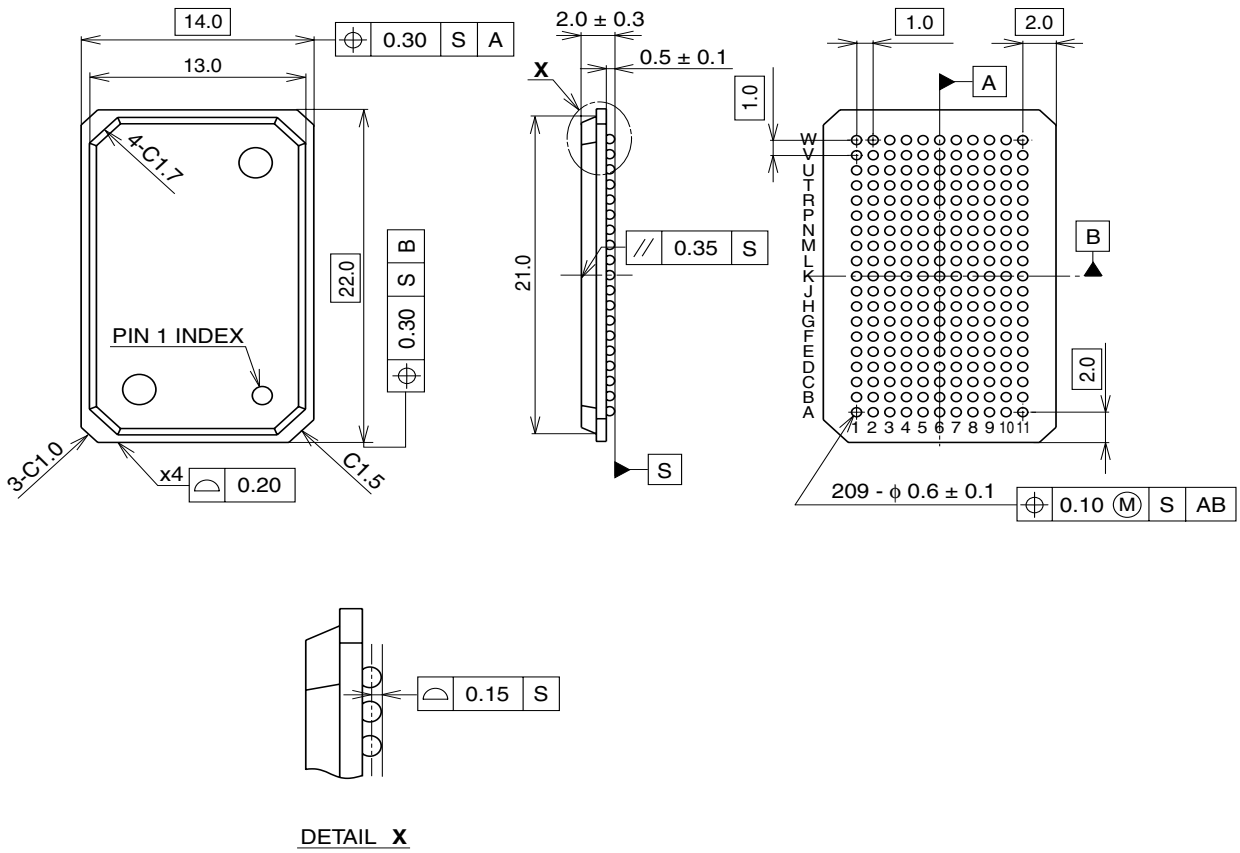
Note 2: This MCH pin is connected to V_{DD} internally, regardless of pin connection externally.

•Ordering Information

Part Number	V_{DD}	I/O Type	Configuration	Speed (Cycle Time / Data Access Time)
CXK79M36C162GB-33	1.8V	HSTL	512Kb x 36	3.3ns / 1.8ns
CXK79M36C162GB-4	1.8V	HSTL	512Kb x 36	4.0ns / 2.1ns
CXK79M36C162GB-5	1.8V	HSTL	512Kb x 36	5.0ns / 2.3ns

•(11x19) 209 Pin BGA Package Dimensions

209PIN BGA (PLASTIC)



DETAIL **X**

PRELIMINARY

SONY CODE	BGA-209P-01
JEITA CODE	P-BGA209-14X22-1.0
JEDEC CODE	————

PACKAGE STRUCTURE

PACKAGE MATERIAL	EPOXY RESIN
TERMINAL TREATMENT	COPPER-CLAD LAMINATE
TERMINAL MATERIAL	SOLDER
PACKAGE MASS	1.1g

•Revision History

Rev. #	Rev. Date	Description of Modifications
rev 0.0	02/23/01	Initial Version.
rev 0.1	07/06/01	1. Modified DC Electrical Characteristics section (p. 9). Added I_{DD-33} and I_{DD-44} Average Power Supply Operating Current specifications. 2. Added 209 Pin BGA Package Dimensions (p. 24).
rev 0.2	02/22/02	1. Added BGA Package Thermal Characteristics (p. 8). 2. Modified AC Electrical Characteristics section (p. 11). Removed "-44" bin. Added "-5" bin. -4 t_{CHCL} $t_{KHKL} \pm 0.12$ to $t_{KHKL} \pm 0.1$ t_{CLCH} $t_{KLKH} \pm 0.12$ to $t_{KLKH} \pm 0.1$ 3. Added JTAG ID Codes (p. 21). 4. Added JTAG Boundary Scan Register Bit Order Assignments (pp. 22-23).
rev 1.0	07/19/02	1. Modified Pin Assignment section (p. 2-4). Pin 1K: CQ to $\overline{CQ2}$ Pin 2K: $\overline{CQ}$ to $\overline{CQ2}$ Pin 10K: $\overline{CQ}$ to $\overline{CQ1}$ Pin 11K: CQ to CQ1 Pin 6J: M4 to MCH Pin 6L: M2 to MCL Pin 6M: M3 to MCH 2. Modified I/O Capacitance section (p. 8). C_{KIN}: 3.5pF to 4.0pF 3. Modified DC Recommended Operating Conditions section (p. 9). Combined -1.8 and -1.5 line items into one for V_{DDQ}, V_{REF}, and V_{CM}. V_{REF} (min): 0.65V to $V_{DDQ}/2$ - 0.1V V_{REF} (max): 1.0V to $V_{DDQ}/2$ + 0.1V V_{CM} (min): 0.65V to $V_{DDQ}/2$ - 0.1V V_{CM} (max): 1.0V to $V_{DDQ}/2$ + 0.1V Removed notes 1 and 2. 4. Modified DC Electrical Characteristics section (p. 10). Added MCH and MCL Input Leakage Current specifications. Reduced x36 Average Power Supply Operating Currents by 100mA. Reduced x18 Average Power Supply Operating Currents by 50mA. 5. Modified AC Electrical Characteristics section (p. 11). -33 t_{KHCH} (max), t_{KLCL} (max), t_{KHCZ}: 1.7ns to 1.8ns -4 t_{KHCH} (max), t_{KLCL} (max), t_{KHCZ}: 2.0ns to 2.1ns -5 t_{KHCH} (max), t_{KLCL} (max), t_{KHCZ}: 2.2ns to 2.3ns 6. Modified JTAG DC Recommended Operating Conditions section (p. 17). V_{TIH} (min): 1.2V to $V_{DD}/2$ + 0.3V V_{TIL} (max): 0.6V to $V_{DD}/2$ - 0.3V I_{TLI} (min): -10uA to -20uA 7. Modified JTAG AC Electrical Characteristics section (p. 18). t_{THTH}: 20ns to 50ns t_{THTL}, t_{TLTH}: 8ns to 20ns Added t_{CS} Capture Setup and t_{CH} Capture Hold specifications. 8. Modified TAP Registers section (p. 20). Instruction Register Codes 011, 110: Bypass to Private 9. Modified Boundary Scan Register Bit Order Assignments section (p. 22). x36 Bit 29: 10A to 11A x36 Bit 30: 11A to 10A

Rev. #	Rev. Date	Description of Modifications
rev 1.1	11/08/02	1. Removed x18 organization and all related references. 2. Modified Pin Description section (p. 3). For NC pins, removed reference to V_{DD} and V_{DDQ}. 3. Modified AC Electrical Characteristics section (p. 10). -33 t_{CHQV}, t_{CLQV} 0.2ns to 0.25ns t_{CHQX}, t_{CLQX} -0.2ns to -0.25ns Removed t_{CHCL} and t_{CLCH} Output Clock High and Low Pulse Width specifications. 4. Modified JTAG AC Electrical Characteristics section (p. 17). t_{CH} 5ns to 8ns Added Note 1 for t_{CS} and t_{CH} specifications.